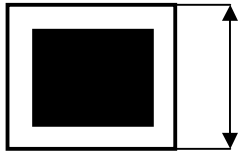


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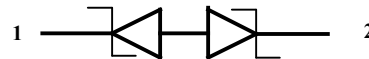
SMB-05L31; SMB-05L32

Chip Bi- directional TVS diode in wafer form, 4 inch.

Die size: 15*15mil.



A


Mechanical data: $A_x = 380\mu\text{m}$. $A_y = 380\mu\text{m}$.

Chip thickness: a) $460 \pm 20\mu\text{m}$ – for SMB-05L31;

 b) $230 \pm 20\mu\text{m}$ – for SMB-05L32;

Top Metal: Al- for wire bonding.

Back side: a) SMB-05L31 - without metallization;

b) SMB-05L32 – Ti-Ni-Ag for Soldering.

Probing: a) **sampling testing:** no bad dice inking;

 guaranteed good dice quantity $\geq 95\%$.

b) 100% testing (if agreed with customer): wafer mapping data;

no bad dice inking.

Limiting values

Parameter	Symbol	Conditions	Value	Unit
Working Peak Reverse Voltage	V_{RWM}		5,0.	V
Peak Pulse Power	P_{pp}	$t_p = 8/20\mu\text{s}$	140*	W
Peak Pulse Current	I_{pp}	$t_p = 8/20\mu\text{s}$	10,0*	A
Electrostatic Discharge	V_{ESD}	IEC 61000-4-2, level 4.	+/-8,0 (Contact); +/-15,0 (Air).	kV
Max. junction temperature	T_j		+150	°C

Characteristics . $T_j = 25^\circ\text{C}$.

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
I_R	Diode reverse leakage current.	$V = \pm 5,0 \text{ V}$	-	-	90	nA
V_{BR}	Breakdown voltage.	$I_R = 1 \text{ mA}$	5,6	-	9,4	V
C_j	Diode capacitance.	$F = 1 \text{ MHz}$, $V_{dc} = 0 \text{ V}$.	-	15	20	pF
V_{CL}	Clamping voltage	$I_{pp} = 1,0 \text{ A}$; $I_{pp} = 10,0 \text{ A}$; $t_p = 8/20\mu\text{s}$.	-	-	12,0* 14,0*	V

*For Device testing